

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				ATTY DOCKET NO. ITO.0508US (P12501)		SERIAL NO. 09/975,163	
				APPLICANT(S): DANIEL XU			
				FILING DATE: October 11, 2001		GROUP ART UNIT: 2823	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	A.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	B.						
	C.						
	D.						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	E.						
	F.						
	G.						
	H.						
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
BU	I.	Hwang, Y.N., Hong, J.S., Lee, S.H., Ahn, S.J., Jeong, G.T., Koh, G.H., Kim, H.J., Jeong, W.C., Lee, S.Y., Park, J.H., Ryoo, K.C., Horii, H., Ha, Y.H., Yi, J.H., Cho, W.Y., Kim, Y.T., Lee, K.H., Joo, S.H., Park, S.O., Jeong, U.I., Jeong, H.S. and Kim, Kinam, "Completely CMOS-Compatible Phase-Change Nonvolatile RAM Using NMOS Cell Transistors," presented at 2003 19 th IEEE Non-Volatile Semiconductor Memory Workshop, Monterey, California, February 26-20, 2003					
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	M.						
	N.						
	O.						
EXAMINER <i>Brook Keshede</i>				DATE CONSIDERED <i>6/1/2004</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							